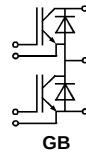


SEMITRANS® M IGBT Modules SKM 100 GB 173 D



SEMITRANS 2



Features

- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \cdot I_{Cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding
- Large clearance (10 mm) and creepage distances (20 mm).

Typical Applications:

- AC inverter drives on mains 575 - 750 V_{AC}
- DC bus voltage 750 - 1200 V_{DC}
- Public transport (auxiliary syst.)
- Switching (not for linear use)

1) $T_{case} = 25^\circ\text{C}$, unless otherwise specified

2) $I_F = -I_C$, $V_R = 1200\text{ V}$,

$-di_F/dt = 800\text{ A}/\mu\text{s}$, $V_{GE} = 0\text{ V}$

8) CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B6 - 52

Absolute Maximum Ratings		Values	Units
Symbol	Conditions ¹⁾		
V_{CES}		1700	V
V_{CGR}	$R_{GE} = 20\text{ k}\Omega$	1700	V
I_C	$T_{case} = 25/80^\circ\text{C}$	110 / 75	A
I_{CM}	$T_{case} = 25/80^\circ\text{C}$; $t_p = 1\text{ ms}$	220 / 150	A
V_{GES}		± 20	V
P_{tot}	per IGBT, $T_{case} = 25^\circ\text{C}$	625	W
T_J , (T_{stg})		$-40 \dots +150$ (125)	$^\circ\text{C}$
V_{isol}	AC, 1 min.	4000	V
humidity	DIN 40 040	Class F	
climate	DIN IEC 68 T.1	55/150/56	

Inverse Diode ⁸⁾			
Symbol	Conditions ¹⁾		Units
$I_F = -I_C$	$T_{case} = 25/80^\circ\text{C}$	80 / 50	A
$I_{FM} = -I_{CM}$	$T_{case} = 25/80^\circ\text{C}$; $t_p = 1\text{ ms}$	200 / 150	A
I_{FSM}	$t_p = 10\text{ ms}$; $\sin$; $T_J = 150^\circ\text{C}$	720	A
I^2t	$t_p = 10\text{ ms}$; $T_J = 150^\circ\text{C}$	2600	A^2s

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
$V_{(BR)CES}$	$V_{GE} = 0$, $I_C = 1,4\text{ mA}$	$\geq V_{CES}$	—	—	V
$V_{GE(th)}$	$V_{GE} = V_{CE}$, $I_C = 6\text{ mA}$	4,8	5,5	6,2	V
I_{CES}	$V_{GE} = 0$ $\left\{ \begin{array}{l} T_J = 25^\circ\text{C} \\ V_{CE} = V_{CES} \end{array} \right. T_J = 125^\circ\text{C}$	—	0,1	1	mA
I_{GES}	$V_{GE} = 20\text{ V}$, $V_{CE} = 0$	—	—	400	nA
V_{CESat}	$I_C = 75\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 15\text{ V}; \\ I_C = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$	—	3,4(4,4)	3,9(5)	V
V_{CESat}	$I_C = 100\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 15\text{ V}; \\ I_C = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$	—	3,8(5,5)	—	V
g_{fs}	$V_{CE} = 20\text{ V}$, $I_C = 75\text{ A}$	27	—	—	S
C_{CHC}	per IGBT	—	—	200	pF
C_{ies}	$V_{GE} = 0$	—	11	—	nF
C_{oes}	$V_{CE} = 25\text{ V}$	—	1	—	nF
C_{res}	$f = 1\text{ MHz}$	—	0,28	—	nF
L_{CE}		—	—	30	nH
$t_{d(on)}$	$V_{CC} = 1200\text{ V}$	—	40	—	ns
t_r	$V_{GE} = +15\text{ V} / -15\text{ V}$	—	45	—	ns
$t_{d(off)}$	$I_C = 75\text{ A}$, ind. load	—	400	—	ns
t_f	$R_{Gon} = R_{Goff} = 10\ \Omega$	—	56	—	ns
E_{on}	$T_J = 125^\circ\text{C}$	—	35	—	mWs
E_{off}		—	21	—	mWs

Inverse Diode ⁸⁾					
Symbol	Conditions ¹⁾				Units
$V_F = V_{EC}$	$I_F = 75\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 0\text{ V}; \\ I_F = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$	—	2,2(2,0)	2,7(2,3)	V
$V_F = V_{EC}$	$I_F = 100\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 0\text{ V}; \\ I_F = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$	—	2,45(2,25)	—	V
V_{TO}	$T_J = 125^\circ\text{C}$	—	1,3	1,5	V
r_T	$T_J = 125^\circ\text{C}$	—	9	13	m Ω
I_{RRM}	$I_F = 75\text{ A}$; $T_J = 25$ (125) $^\circ\text{C}$ ²⁾	—	38(51)	—	A
Q_{rr}	$I_F = 75\text{ A}$; $T_J = 25$ (125) $^\circ\text{C}$ ²⁾	—	8(19)	—	μC

$V_F = V_{EC}$	$I_F = 75\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 0\text{ V}; \\ I_F = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$				V
$V_F = V_{EC}$	$I_F = 100\text{ A}$ $\left\{ \begin{array}{l} V_{GE} = 0\text{ V}; \\ I_F = 100\text{ A} \end{array} \right. T_J = 25$ (125) $^\circ\text{C}$				V
V_{TO}	$T_J = 125^\circ\text{C}$				V
r_T	$T_J = 125^\circ\text{C}$				m Ω
t_{rr}	$I_F = 75\text{ A}$; $T_J = 25$ (125) $^\circ\text{C}$ ²⁾				μs
Q_{rr}	$I_F = 75\text{ A}$; $T_J = 25$ (125) $^\circ\text{C}$ ²⁾				μC

Thermal Characteristics					
Symbol	Conditions ¹⁾				Units
R_{thjc}	per IGBT	—	—	0,2	$^\circ\text{C}/\text{W}$
R_{thjd}	per diode	—	—	0,63	$^\circ\text{C}/\text{W}$
R_{thch}	per module	—	—	0,05	$^\circ\text{C}/\text{W}$

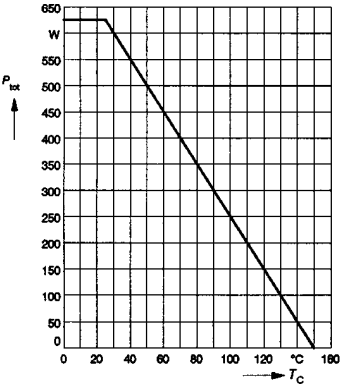


Fig. 1 Rated power dissipation $P_{tot} = f(T_C)$

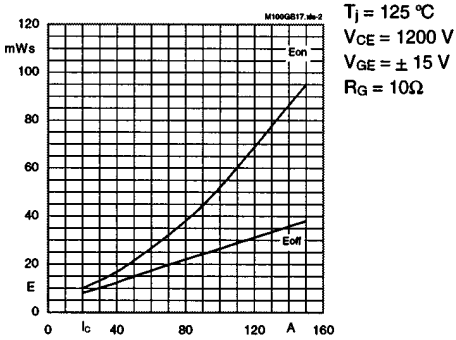


Fig. 2 Turn-on /-off energy = $f(I_C)$

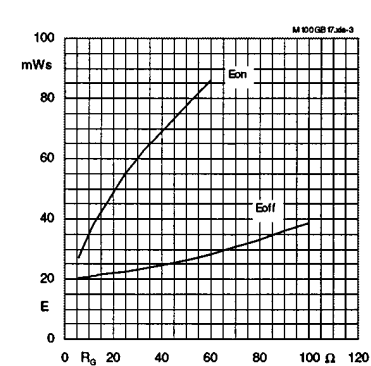


Fig. 3 Turn-on /-off energy = $f(R_G)$

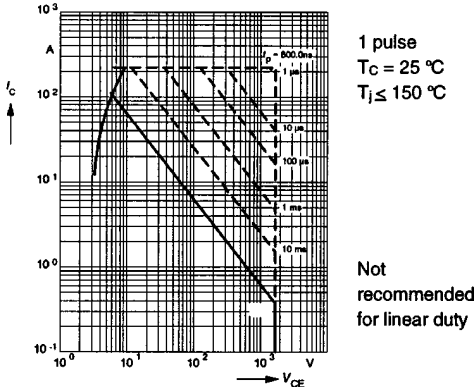


Fig. 4 Maximum safe operating area (SOA) $I_C = f(V_{CE})$

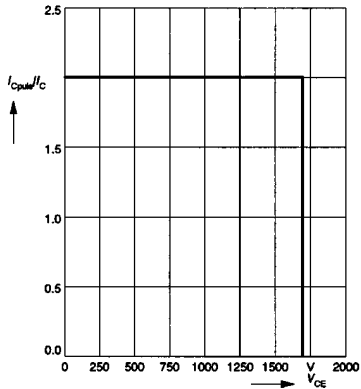


Fig. 5 Turn-off safe operating area (RBSOA)

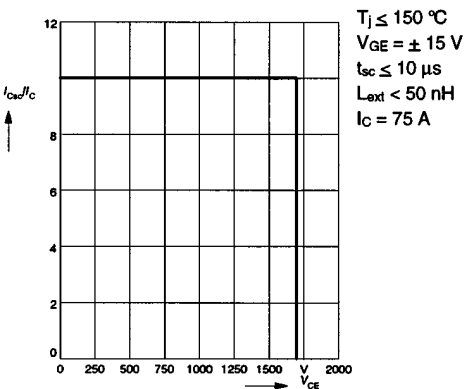


Fig. 6 Safe operating area at short circuit $I_C = f(V_{CE})$

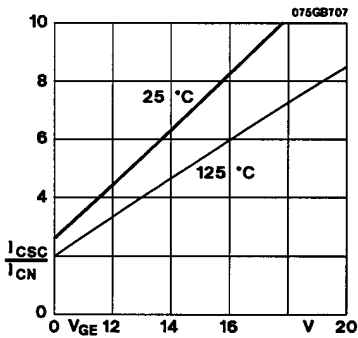


Fig. 7 Short circuit current vs. turn-on gate voltage

$V_C = 1200 \text{ V}$
 $t_p = 10 \mu\text{s}$
 $L_{ext} \leq 25 \text{ nH}$
 $R_{Gon} = 10 \Omega$
 $R_{Goff} = 10 \Omega$

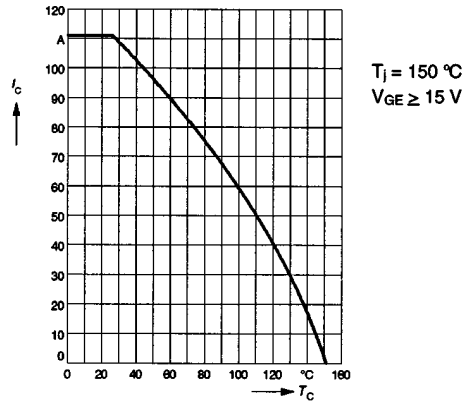


Fig. 8 Rated current vs. temperature $I_C = f(T_C)$

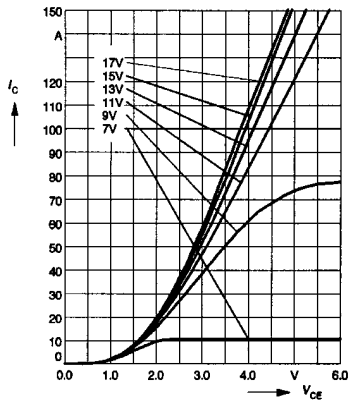


Fig. 9 Typ. output characteristic, $t_p = 80 \mu\text{s}$; $T_J = 25 \text{ °C}$

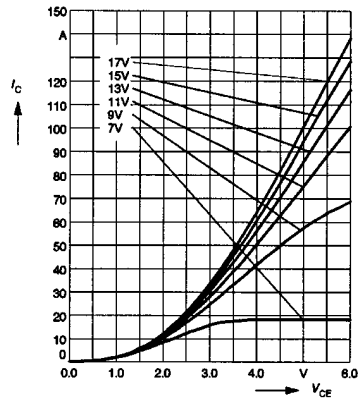


Fig. 10 Typ. output characteristic, $t_p = 80 \mu\text{s}$; $T_J = 125 \text{ °C}$

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_C(t)$$

$$V_{CEsat(t)} = V_{CE(TO)(T_J)} + r_{CE(T_J)} \cdot I_C(t)$$

$$V_{CE(TO)(T_J)} \leq 1,9 + 0,003 (T_J - 25) [\text{V}]$$

$$r_{CE(T_J)} = 0,023 + 0,00007 (T_J - 25) [\Omega]$$

$$\text{valid for } V_{GE} = +15 \frac{+2}{-1} [\text{V}]; I_C > 0,3 I_{Cnom}$$

Fig. 11 Typ. saturation characteristic (IGBT)
 Calculation elements and equations

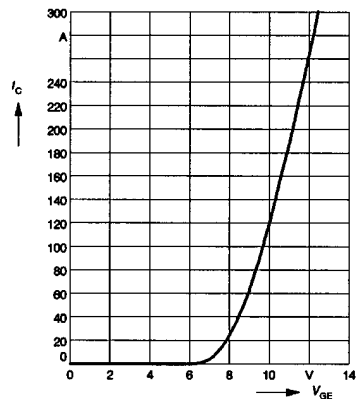


Fig. 12 Typ. transfer characteristic, $t_p = 80 \mu\text{s}$; $V_{CE} = 20 \text{ V}$

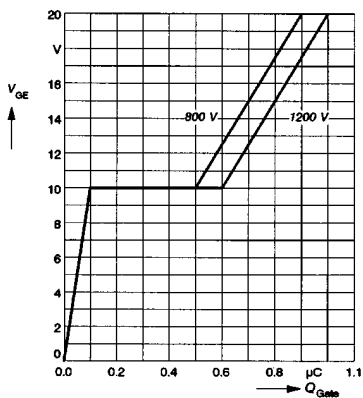


Fig. 13 Typ. gate charge characteristic

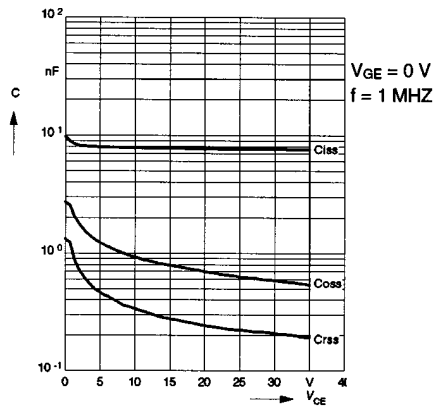


Fig. 14 Typ. capacitances vs. V_{CE}

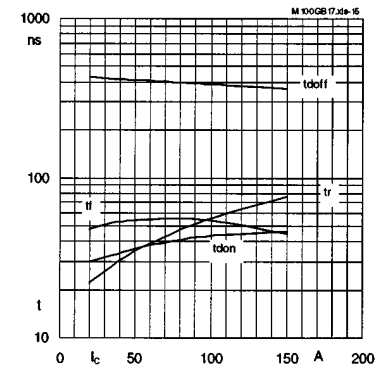


Fig. 15 Typ. switching times vs. I_C

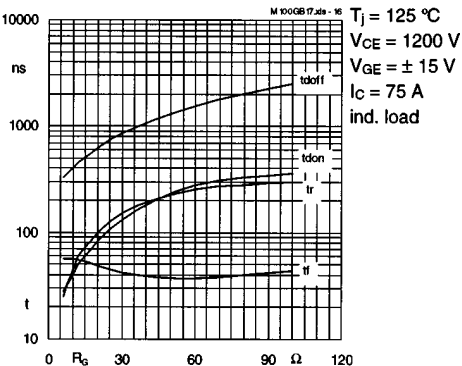


Fig. 16 Typ. switching times vs. R_G

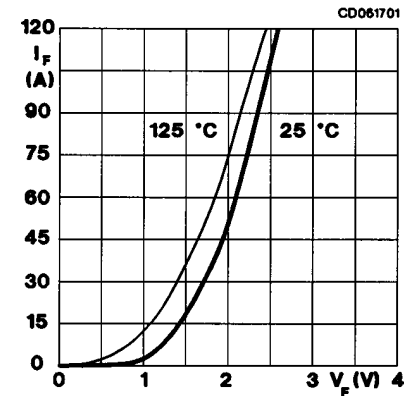


Fig. 17 Typ. CAL diode forward characteristic

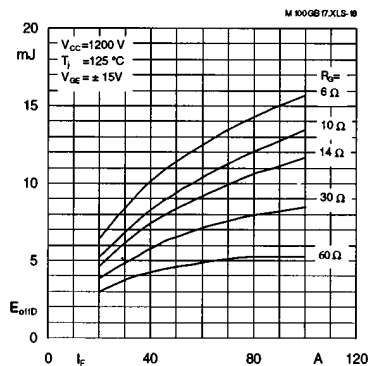


Fig. 18 Typ. Diode turn-off energy dissipation per pulse

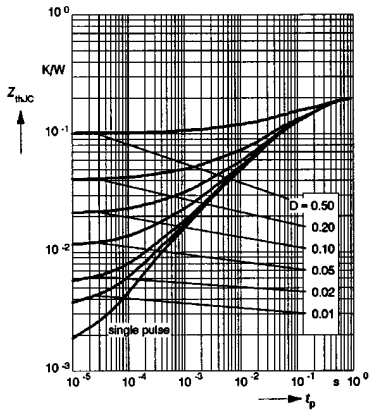


Fig. 19 Transient thermal impedance of IGBT: $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

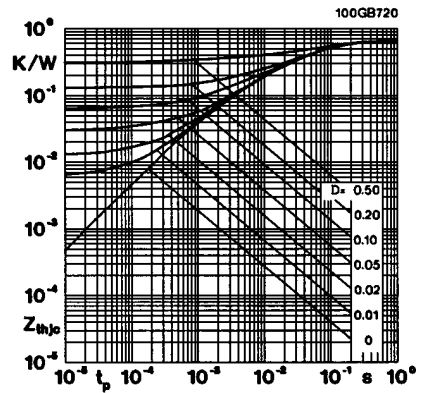


Fig. 20 Transient thermal impedance of inverse diode: $Z_{thJC} = f(t_p)$

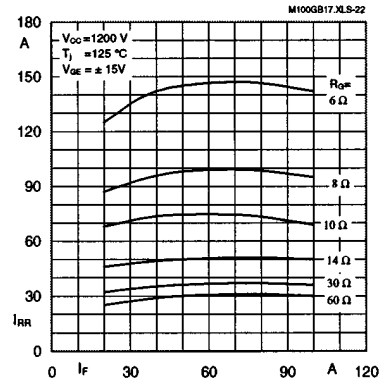


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

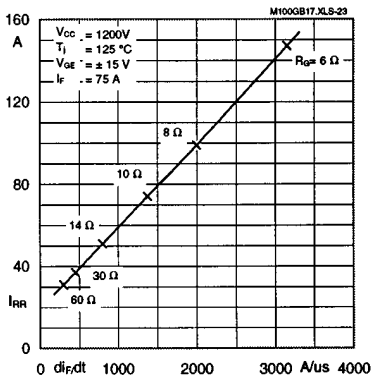


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(di_F/dt)$

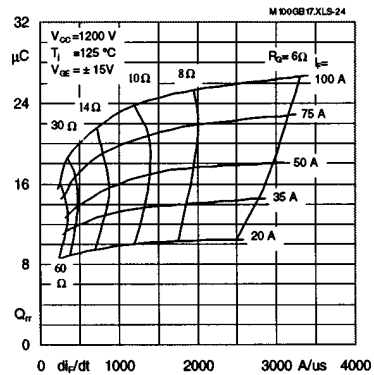


Fig. 24 Typ. CAL diode recovered charge Q_{rr}

SEMITRANS 2

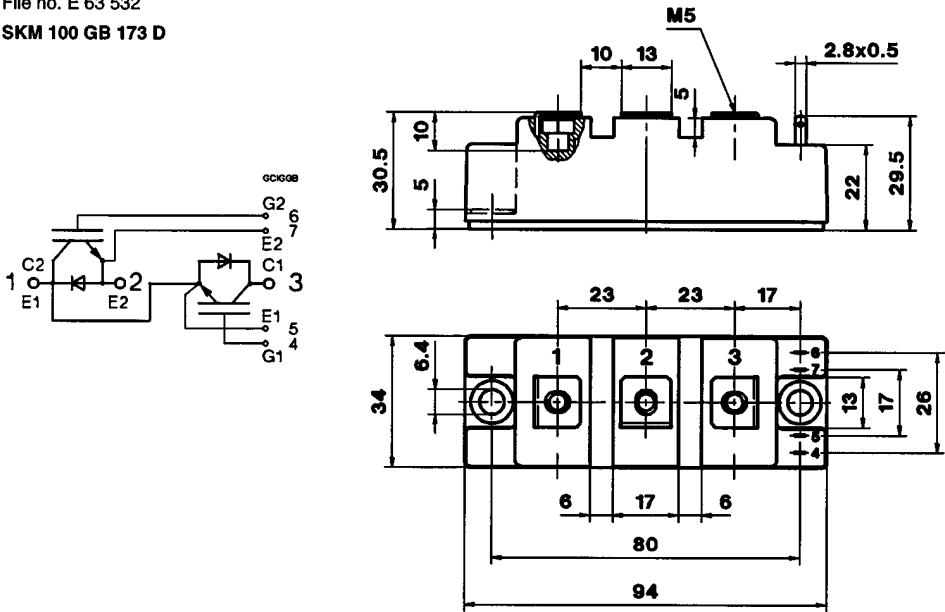
Case D 61

UL Recognized

File no. E 63 532

SKM 100 GB 173 D

CASED61



Dimensions in mm

Case outline and circuit diagrams

Mechanical Data		Values			Units
Symbol	Conditions	min.	typ.	max.	
M ₁	to heatsink, SI Units (M6)	3	—	5	Nm
	to heatsink, US Units	27	—	44	lb.in.
M ₂	for terminals, SI Units (M5)	2,5	—	5	Nm
	for terminals US Units	22	—	44	lb.in.
a		—	—	5x9,81	m/s ²
w		—	—	250	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Eight devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 2). Larger packaging units of 20 or 42 pieces are used if suitable.

Accessories → page B 6 - 4.
SEMIBOX → page C - 1.